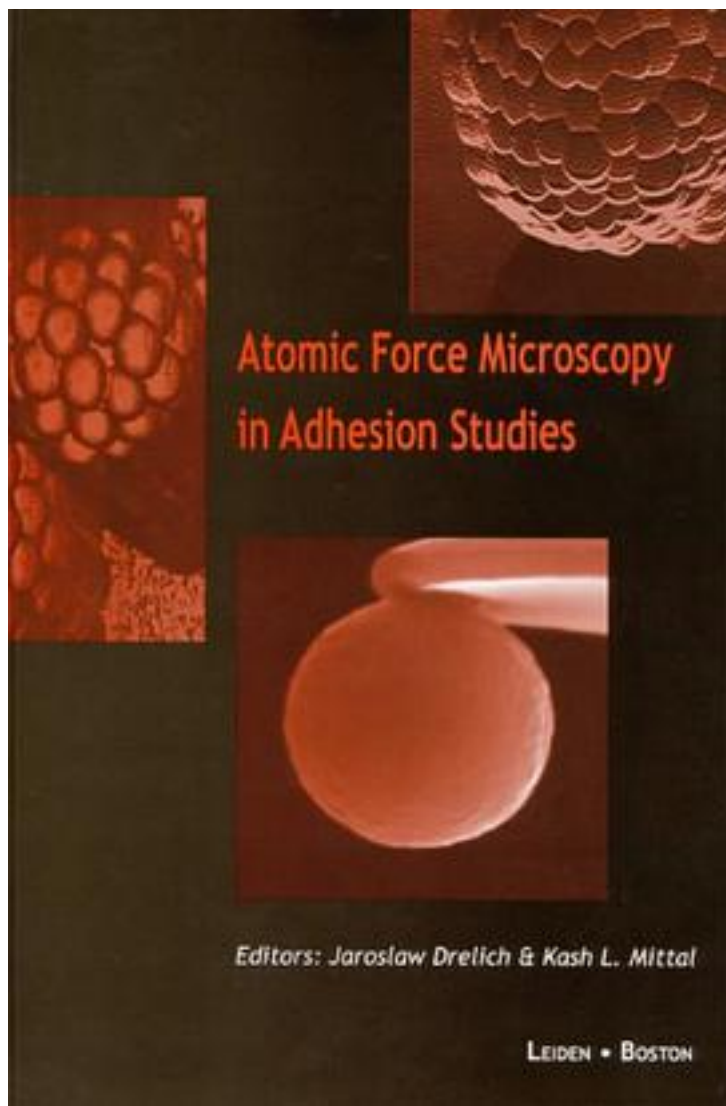


Atomic Force Microscopy in Adhesion Studies



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Since its discovery, Atomic Force Microscopy (AFM) has become a technique of choice for non-destructive surface characterization with sub-molecular resolution. The AFM has also emerged as a problem-solving tool in applications relevant to particle-solid and particle-liquid interactions, design, fabrication, and characterization of new materials, and development of new technologies for processing and modification of materials. This volume is a comprehensive review of AFM techniques and their application in adhesion studies. It is intended for both researchers and students in engineering disciplines, physics and biology. Over 100 authors contributed to this book, summarizing current status of research on measurements of colloidal particle-solid adhesion and molecular forces, solid surface imaging and mapping, and discussing the contact mechanics models applicable to particle-substrate and particle-particle systems.

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